

ABSTRACT OF THE DISCLOSURE

An apparatus enables a high quality test to be carried out within a short time, without forcing a severe design limitation on the designer and without an expensive tester. The apparatus comprises a pattern generator built in an integrated circuit to generate a test pattern, a plurality of shift registers configured with sequential circuit elements^L F/Fs[?] inside the integrated circuit, and a pattern modifier modifying the test pattern generated by the pattern generator according to an external input, and inputting it to the plural shift registers. The apparatus is used as a testing apparatus for detecting manufacturing failure of an integrated circuit such as an LSI (Large Scale Integration) or the like.